

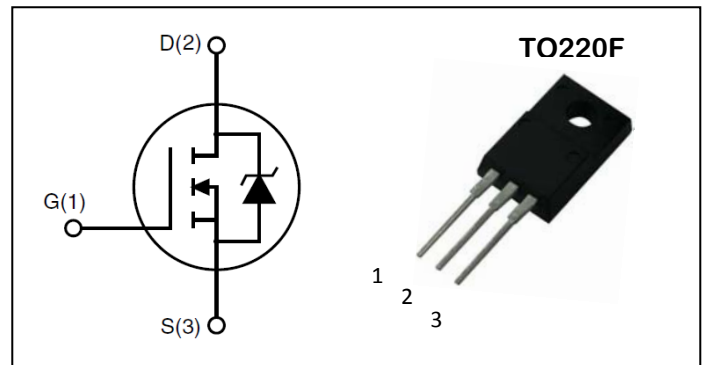
N-Channel Enhancement Mode Field Effect Transistor

PRODUCT SUMMARY

| | | |
|-----------|-------|----------------------------|
| V_{DSS} | I_D | $R_{DS(ON)}$ (m Ω) |
| 600V | 20A | 135m Ω |

Features:

- Low gate input resistance
- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Lead-Free, RoHS Compliant



Description:

The ADM26N60F series MOSFETs is a new technology, which combines an innovative super junction technology and advance process. This new technology achieves low R_{ds(on)}, energy saving, high reliability and uniformity, superior power density and space saving.

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | | Ratings | Unit |
|-----------------------------------|---|-------------------------|------------|---------------------|
| Common Ratings | | | | |
| V_{DSS} | Drain-Source Voltage | | 600 | V |
| V_{GSS} | Gate-Source Voltage | | ± 30 | |
| T_J | Maximum Junction Temperature | | 150 | $^\circ\text{C}$ |
| T_{STG} | Storage Temperature Range | | -55 to 150 | $^\circ\text{C}$ |
| I_S | Diode Continuous Forward Current | $T_C=25^\circ\text{C}$ | 20 | A |
| Mounted on Large Heat Sink | | | | |
| I_{DM} | 300 μs Pulse Drain Current Tested(1) | $T_C=25^\circ\text{C}$ | 80 | A |
| I_D | Continuous Drain Current | $T_C=25^\circ\text{C}$ | 20 | A |
| | | $T_C=100^\circ\text{C}$ | 13 | A |
| P_D | Power Dissipation | $T_C=25^\circ\text{C}$ | 35 | W |
| | Derating factor | | 0.28 | W/ $^\circ\text{C}$ |

1. Pulse width limited by maximum junction temperature.

Thermal Characteristics

| Symbol | Parameter | Ratings | Unit |
|------------|---|---------|---------------------------|
| R_{thJC} | Thermal resistance junction-case max | 3.6 | $^\circ\text{C}/\text{W}$ |
| R_{thJA} | Thermal resistance junction-ambient max | 62.5 | $^\circ\text{C}/\text{W}$ |

Electrical Characteristics (TA=25°C Unless Otherwise Noted)

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------------------|---|---|------|------|------|------|
| On/off Characteristics | | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} =0V, I _{DS} =1mA | 600 | -- | -- | V |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 600V, V _{GS} =0V | -- | -- | 1 | uA |
| | | V _{DS} =600V, V _{GS} =0V T _J =125°C | -- | -- | 50 | |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} =V _{GS} , I _{DS} =250uA | 2 | 3 | 4 | V |
| I _{GSS} | Gate Leakage Current | V _{GS} =±30V, V _{DS} =0V | -- | -- | ±100 | nA |
| R _{DS(ON)} | Drain-Source On-state Resistance ⁽²⁾ | V _{GS} = 10V, I _{DS} =13A | -- | 135 | 165 | mΩ |
| Dynamic Characteristics | | | | | | |
| C _{iss} | Input Capacitance | V _{GS} =0V, V _{DS} = 50V, Frequency=1MHz | -- | 1474 | -- | pF |
| C _{oss} | Output Capacitance | | -- | 149 | -- | |
| C _{rss} | Reverse Transfer Capacitance | | -- | 4 | -- | |
| Switching Characteristics | | | | | | |
| t _{d(ON)} | Turn-on Delay Time ⁽¹⁾ | V _{DS} =300V, I _D = 10A, V _{GS} = 10V, R _{GEN} =4.7 Ω R _L =30 Ω | -- | 15.2 | -- | ns |
| t _r | Turn-on Rise Time ⁽¹⁾ | | -- | 18.2 | -- | |
| t _{d(OFF)} | Turn-off Delay Time ⁽¹⁾ | | -- | 46.0 | -- | |
| t _f | Turn-off Fall Time ⁽¹⁾ | | -- | 15.7 | -- | |
| Q _g | Total Gate Charge ⁽¹⁾ | V _{DS} =480V, V _{GS} = 10V, I _{DS} =20A | -- | 52.1 | -- | nC |
| Q _{gs} | Gate-Source Charge ⁽¹⁾ | | -- | 11.2 | -- | |
| Q _{gd} | Gate-Drain Charge ⁽¹⁾ | | -- | 24.9 | -- | |
| Diode Characteristics | | | | | | |
| V _{SD} | Diode Forward Voltage ⁽²⁾ | I _{SD} = 20A, V _{GS} = 0 | -- | 0.87 | 1.3 | V |
| t _{rr} | Reverse Recovery Time | I _{SD} =20A, dI _{SD} /dt=100A/μs | -- | 370 | -- | ns |
| q _{rr} | Reverse Recovery Charge | | -- | 5 | -- | uC |

NOTES:

- Independent of operating temperature.
- Pulse Test : Pulse width ≤ 300 μs, Duty cycle ≤ 2%

Typical Performance Characteristics

Figure 1: Typical Output Characteristics

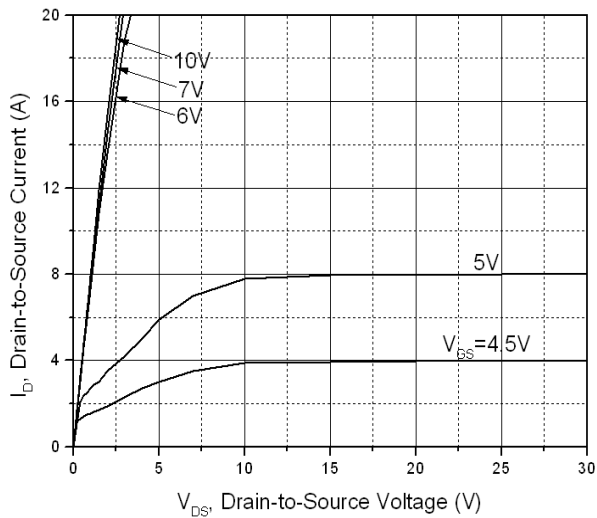


Figure 2: Typ. Gate to source cut-off voltage

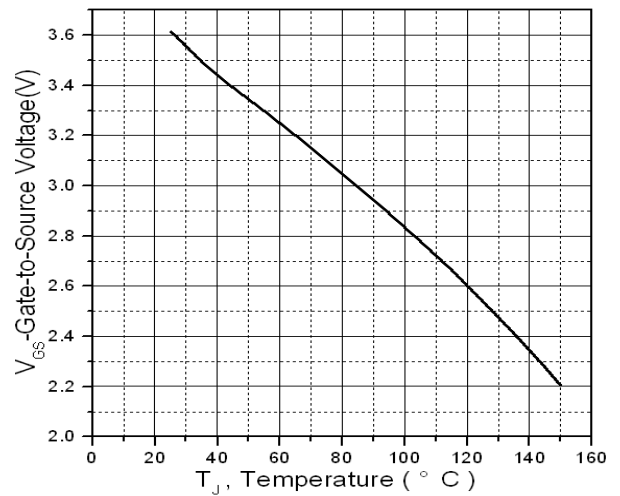


Figure 3: Drain-to-Source Breakdown Voltage vs. Temperature

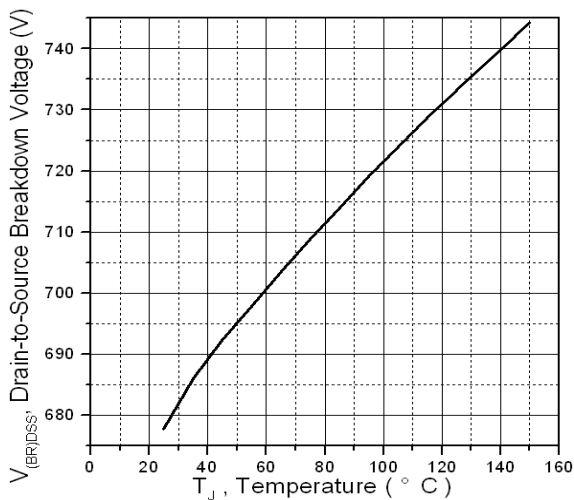


Figure 4: Normalized On-Resistance Vs. Case Temperature

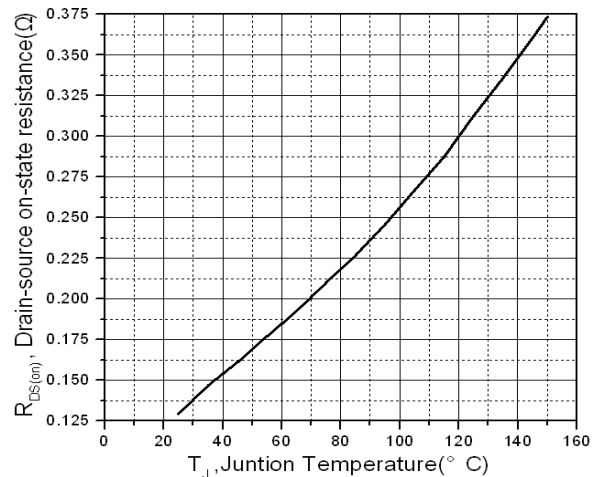


Figure 5: Maximum Drain Current Vs. Case Temperature

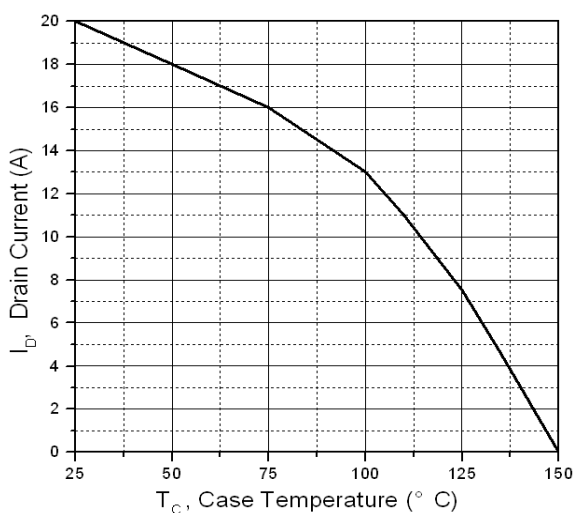
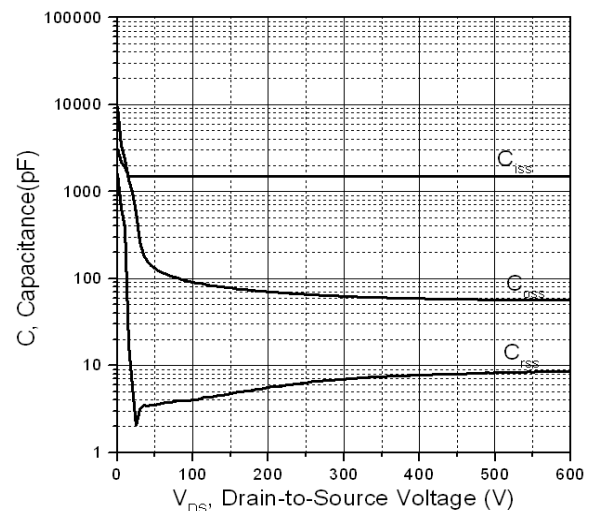
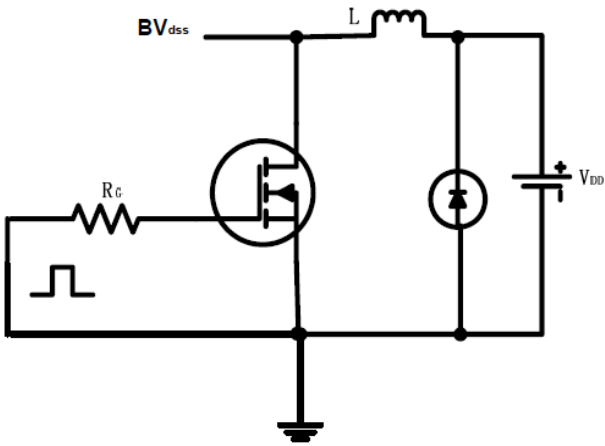


Figure 6: Typical Capacitance Vs. Drain-to-Source Voltage

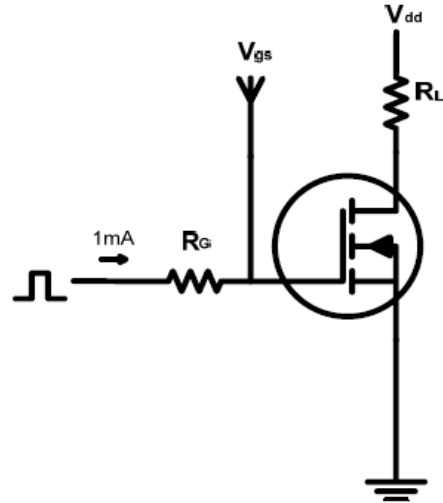


Test circuits and Waveforms

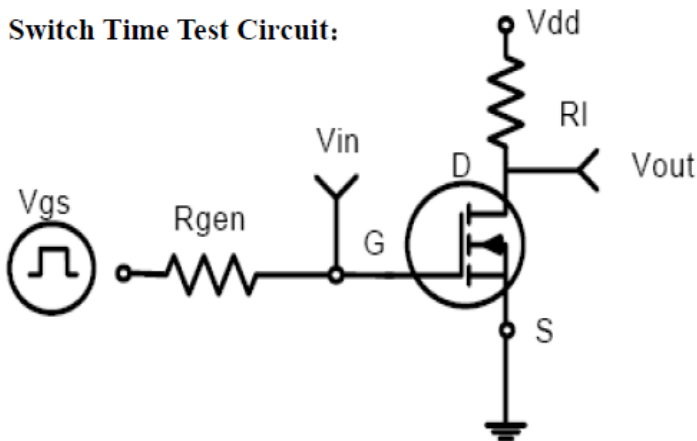
EAS test circuits:



Gate charge test circuit:



Switch Time Test Circuit:



Switch Waveforms:

